

## Standard Power MOSFET

### IXTH50P10 IXTT50P10

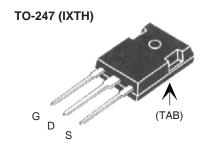
P-Channel Enhancement Mode Avalanche Rated



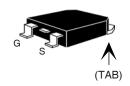
Symbol	Test Conditions	Maximum F	Ratings
V <sub>DSS</sub>	T <sub>_</sub> = 25°C to 150°C	-100	V
V <sub>DGR</sub>	$T_J = 25^{\circ}\text{C to } 150^{\circ}\text{C}, R_{GS} = 1\text{M}\Omega$	-100	V
V <sub>GSS</sub>	Continuous	±20	V
V <sub>GSM</sub>	Transient	±30	V
I <sub>D25</sub>	T <sub>c</sub> = 25°C	- 50	A
I <sub>DM</sub>	$T_{\rm c}$ = 25°C, pulse width limited by $T_{\rm JM}$	- 200	Α
I <sub>A</sub>	T <sub>c</sub> = 25°C	- 50	A
E <sub>AS</sub>	$T_c = 25^{\circ}C$	30	mJ
$P_{D}$	T <sub>C</sub> = 25°C	300	W
T		- 55 +150	°C
T <sub>JM</sub>		150	°C
T <sub>stg</sub>		- 55 +150	°C
T <sub>L</sub>	1.6mm (0.062 in.) from case for 10s	300	°C
T <sub>SOLD</sub>	Plastic body for 10s	260	°C
M <sub>d</sub>	Mounting torque (TO-247)	1.13 / 10	Nm/lb.in.
Weight	TO-247 TO-268	6 5	g g

Symbol (T <sub>J</sub> = 25°C,	Test Conditions unless otherwise specified)			cterist		
BV <sub>DSS</sub>	$V_{GS} = 0V, I_{D} = -250 \mu\text{A}$		-100			V
V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$		- 3.0		- 5.0	V
I <sub>GSS</sub>	$V_{GS} = \pm 20V, V_{DS} = 0V$				±100	nA
I <sub>DSS</sub>	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0V$	T <sub>J</sub> = 125°C			- 25 -1	μA mA
R <sub>DS(on)</sub>	$V_{GS} = -10V, I_{D} = 0.5 \cdot I_{D25}, Not$	e 1			55	mΩ

 $V_{DSS} = -100V$   $I_{D25} = -50A$   $R_{DS(on)} \le 55m\Omega$ 



#### TO-268 (IXTT)



G = Gate D = Drain S = Source TAB = Drain

#### **Features**

- International standard packages JEDEC TO-247 AD
- $^{\bullet} \ \mathsf{Low} \ \mathsf{R}_{\mathsf{DS}(\mathsf{ON})} \ \mathsf{HDMOS}^{\mathsf{TM}} \mathsf{process}$
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance (< 5nH)</li>
  - easy to drive and to protect

#### **Applications**

- High side switching
- Push-pull amplifiers
- DC Choppers
- Automatic test equipment

#### Advantages

- Easy to mount with 1 screw (isolated mounting screw hole)
- Space savings
- High power density



Symbol (T <sub>J</sub> = 25		Test Conditions nless otherwise specified)	Ci Min.		stic Values Max.
g <sub>fs</sub>		$V_{DS} = -10V, I_{D} = 0.5 \bullet I_{D25}, \text{ Note 1}$	13	22	S
C <sub>iss</sub>	)			4350	pF
C <sub>oss</sub>	}	$V_{GS} = 0V, V_{DS} = -25V, f = 1MHz$		1505	pF
$\mathbf{C}_{rss}$	J			733	pF
t <sub>d(on)</sub>	)	Resistive Switching Times		46	ns
t <sub>r</sub>		$V_{GS} = -10V, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = 0.5 \cdot I_{D25}$		39	ns
$\mathbf{t}_{d(off)}$		00 20 200 2		86	ns
t <sub>f</sub>	J	$R_{_{\rm G}} = 4.7\Omega \text{ (External)}$		38	ns
$\mathbf{Q}_{g(on)}$	)			140	nC
$\mathbf{Q}_{gs}$	}	$V_{GS} = -10V$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_{D} = 0.5 \cdot I_{D25}$		25	nC
$\mathbf{Q}_{gd}$	J			85	nC
R <sub>thJC</sub>					0.42 °C/W
$\mathbf{R}_{\mathrm{thCS}}$				0.25	°C/W

#### Source-Drain Diode

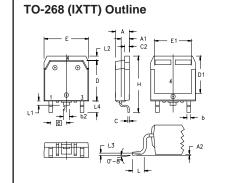
<b>Symbol</b> (Τ <sub>J</sub> = 25°C, ι	Test Conditions Chanless otherwise specified) Min.	aracteris Typ.	tic Valu Max.	es
I <sub>s</sub>	$V_{GS} = 0V$		- 50	Α
I <sub>SM</sub>	Repetitive, pulse width limited by $T_{_{\rm JM}}$		- 200	Α
V <sub>SD</sub>	$I_{\rm F} = -25 A, V_{\rm GS} = 0 V, \text{ Note 1}$		- 3.0	V
t <sub>rr</sub>	$I_F = -25A$ , di/dt = -100A/ $\mu$ s, $V_R = -50V$ , $V_{GS} = 0V$	180		ns

Note 1: Pulse test,  $t \le 300\mu s$ ; duty cycle,  $d \le 2\%$ .

# TO-247 (IXTH) Outline

Terminals: 1 - Gate 2 - Drain

Dim.	Millimeter		Inc	Inches	
	Min.	Max.	Min.	Max.	
Α	4.7	5.3	.185	.209	
A,	2.2	2.54	.087	.102	
A <sub>2</sub>	2.2	2.6	.059	.098	
b	1.0	1.4	.040	.055	
b <sub>1</sub>	1.65	2.13	.065	.084	
b <sub>2</sub>	2.87	3.12	.113	.123	
С	.4	.8	.016	.031	
D	20.80	21.46	.819	.845	
E	15.75	16.26	.610	.640	
е	5.20	5.72	0.205	0.225	
L	19.81	20.32	.780	.800	
L1		4.50		.177	
ØP	3.55	3.65	.140	.144	
Q	5.89	6.40	0.232	0.252	
R	4.32	5.49	.170	.216	



MYZ			MILLIN	METERS .	
2114	MIN	MAX	MIN	MAX	
Α	.193	.201	4.90	5.10	
A1	.106	.114	2.70	2.90	
A2	.001	.010	0.02	0.25	
b	.045	.057	1.15	1.45	
b2	.075	.083	1.90	2.10	
С	.016	.026	0.40	0.65	
C2	.057	.063	1.45	1.60	
D	.543	.551	13.80	14.00	
D1	.488	.500	12.40	12.70	
E	.624	.632	15.85	16.05	
E1	.524	.535	13.30	13.60	
е	.215	BSC	5.45 BSC		
Н	.736	.752	18.70	19.10	
L	.094	.106	2.40	2.70	
L1	.047	.055	1.20	1.40	
L2	.039	.045	1.00	1.15	
L3	.010	BSC	0.25 BSC		
L4	.150	.161	3.80	4.10	

Fig. 1. Output Characteristics @ 25°C

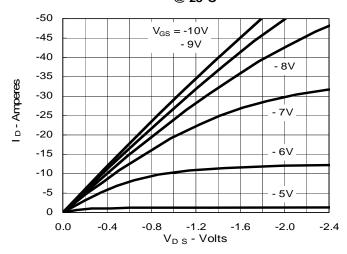


Fig. 3. Output Characteristics @ 125°C

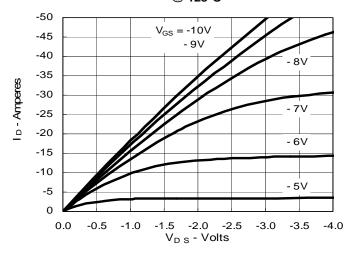


Fig. 5.  $R_{DS(on)}$  Normalized to 0.5  $I_{D25}$   $\,$  Value vs.  $I_{D}$ 

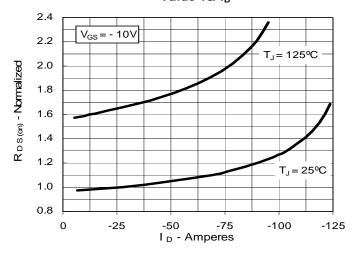


Fig. 2. Extended Output Characteristics
@ 25°C

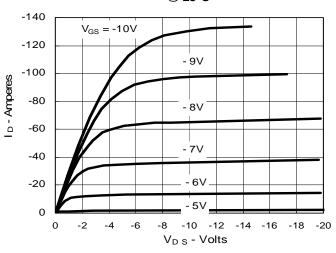


Fig. 4. R<sub>DS(on)</sub> Normalized to 0.5 I<sub>D25</sub> Value vs. Junction Temperature

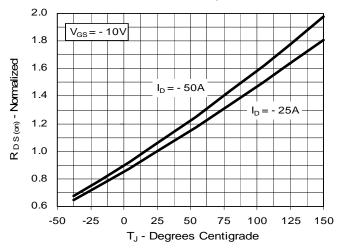


Fig. 6. Drain Current vs. Case Temperature

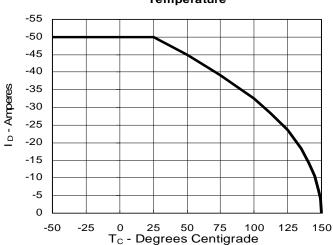


Fig. 7. Input Admittance

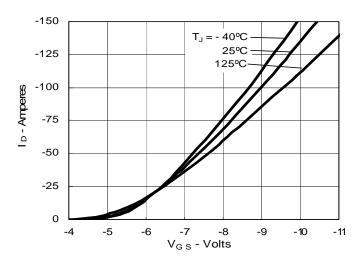


Fig. 9. Source Current vs. Source-To-Drain Voltage

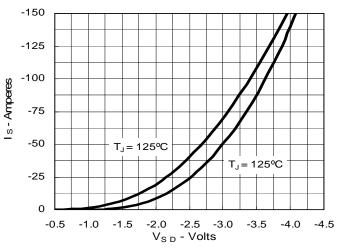
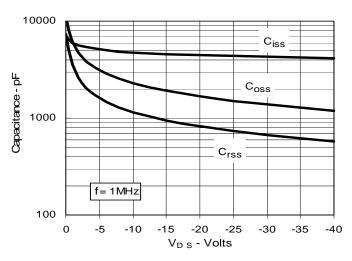


Fig. 11. Capacitance



IXYS reserves the right to change limits, test conditions, and dimensions.

Fig. 8. Transconductance

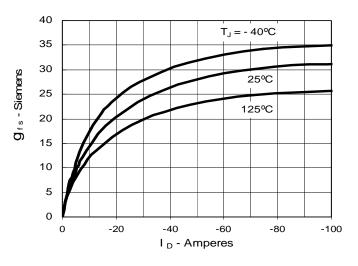


Fig. 10. Gate Charge

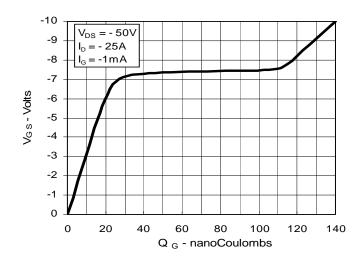


Fig. 12. Maximum Transient Thermal Impedance

